

# C2M0025120D

# Silicon Carbide Power MOSFET C2M MOSFET Technology

N-Channel Enhancement Mode

#### **Features**

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness
- Resistant to Latch-Up
- Halogen Free, RoHS Compliant

#### **Benefits**

- · Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

#### **Applications**

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC converters
- Battery Chargers
- Motor Drive
- Pulsed Power Applications

# **V**<sub>DS</sub> 1200 V

I<sub>D @ 25°C</sub> 63 A

 $R_{DS(on)}$  25 m $\Omega$ 

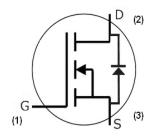
#### Package







TO-247-3



Part Number	Package	Marking		
C2M0025120D	C2M0025120D T0-247-3			

### **Maximum Ratings** (T<sub>c</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note	
V <sub>DSmax</sub>	Drain - Source Voltage	1200	٧	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 100 μA		
$V_{GSmax}$	Gate - Source Voltage	-10/+25	٧	Absolute maximum values		
$V_{GSop}$	Gate - Source Voltage	-5/+20	٧	Recommended operational values		
	Continuous Drain Current	63	А	V <sub>GS</sub> =20 V, T <sub>C</sub> = 25°C	Fig. 19 Note 1	
I <sub>D</sub>		39		V <sub>GS</sub> =20 V, T <sub>C</sub> = 100°C		
I <sub>D(pulse)</sub>	Pulsed Drain Current	250	А	Pulse width t <sub>P</sub> limited by T <sub>jmax</sub>	Fig. 22	
P <sub>D</sub>	Power Dissipation	378	W	T <sub>C</sub> =25°C, T <sub>J</sub> = 150 °C	Fig. 20	
$T_{J}$ , $T_{stg}$	Operating Junction and Storage Temperature	-55 to +150	°C			
T <sub>L</sub>	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s		
M <sub>d</sub>	Mounting Torque	1 8.8	Nm lbf-in	M3 or 6-32 screw		

Note (1): Die limits are 90A (25°C) and 60A (100°C)



## **Electrical Characteristics** (T<sub>c</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note	
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	1200			V	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 100 μA		
	0 . 7	2.0	2.6	4	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 15mA	Fig. 11	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	2.3 V V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 15mA, T <sub>J</sub> = 150 °C		V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 15mA, T <sub>J</sub> = 150 °C	Fig. 11			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		2	100	μΑ	V <sub>DS</sub> = 1200 V, V <sub>GS</sub> = 0 V		
I <sub>GSS</sub>	Gate-Source Leakage Current			250	nA	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V		
R <sub>DS(on)</sub>	Drain-Source On-State Resistance		25	34	mΩ	V <sub>GS</sub> = 20 V, I <sub>D</sub> = 50 A	Fig.	
*DS(on)	Drain Godice on State Resistance		41		11122	V <sub>GS</sub> = 20 V, I <sub>D</sub> = 50 A, T <sub>J</sub> = 150 °C	4,5,6	
$g_{fs}$	Transconductance		24.6		S	V <sub>DS</sub> = 20 V, I <sub>DS</sub> = 50 A	Fig. 7	
915	Transconductance		24		L ŭ	V <sub>DS</sub> = 20 V, I <sub>DS</sub> = 50 A, T <sub>J</sub> = 150 °C	119.7	
$C_{iss}$	Input Capacitance		3140			V <sub>GS</sub> = 0 V		
$C_{\text{oss}}$	Output Capacitance		224		pF	V <sub>DS</sub> = 1000 V	Fig. 17,18	
C <sub>rss</sub>	Reverse Transfer Capacitance		9		]	f = 1 MHz		
E <sub>oss</sub>	C <sub>oss</sub> Stored Energy		128		μJ	Vac = 25 mV	Fig 16	
Eon	Turn-On Switching Energy (Body Diode)		2.18			$V_{DS}$ = 800 V, $V_{GS}$ = -5/20 V, $I_D$ = 50A, $R_{G(ext)}$ = 2.5 $\Omega$ ,L= 99 $\mu$ H FWD = Internal Body Diode of MOSFET	Fig. 25	
E <sub>OFF</sub>	Turn Off Switching Energy (Body Diode)		0.68		mJ			
Eon	Turn-On Switching Energy (External SiC Diode)		1.14		V <sub>DS</sub> = 800 V, V <sub>GS</sub> = -5/20 V,			
E <sub>OFF</sub>	Turn Off Switching Energy (External SiC Diode)		0.8		i mJ	$I_D = 50A$ , $R_{G(ext)} = 2.5\Omega$ , $L = 99 \mu H$ FWD = External SiC Diode	Fig. 25	
$t_{\text{d(on)}}$	Turn-On Delay Time		15			V <sub>DD</sub> = 800 V, V <sub>GS</sub> = -5/20 V	Fig. 27	
$t_{\rm r}$	Rise Time		58			$I_D = 50 \text{ A},$ $R_{G(ext)} = 2.5 \Omega,$ Inductive Load		
$t_{\text{d(off)}} \\$	Turn-Off Delay Time		33		ns	Timing relative to $V_{DS}$		
t <sub>f</sub>	Fall Time		17			Per IEC60747-8-4 pg 83		
$R_{G(int)}$	Internal Gate Resistance		1.0		Ω	f = 1 MHz, V <sub>AC</sub> = 25 mV, ESR of C <sub>ISS</sub>		
$Q_gs$	Gate to Source Charge		46		V <sub>DS</sub> = 800 V, V <sub>GS</sub> = -5/20 V			
$Q_{gd}$	Gate to Drain Charge		71.5		nC	I <sub>D</sub> = 50 A	Fig. 12	
$Q_g$	Total Gate Charge		194			Per IEC60747-8-4 pg 21		



#### **Reverse Diode Characteristics**

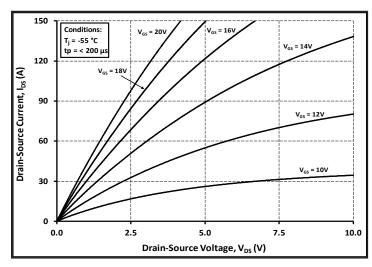
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	4.1		٧	V <sub>GS</sub> = - 5 V, I <sub>SD</sub> = 25 A	Fig. 8, 9,
V SD		3.5		V	$V_{GS} = -5 \text{ V, } I_{SD} = 25 \text{ A, } T_{J} = 150 \text{ °C}$	
Is	Continuous Diode Forward Current		63		$V_{GS} = -5 \text{ V, } T_{C} = 25 \text{ °C}$	Note 2
I <sub>S, pulse</sub>	Diode Pulse Current		250		$V_{GS} = -5 \text{ V}$ , Pulse width $t_P$ limited by $T_{jmax}$	
t <sub>rr</sub>	Reverse Recovery Time	33		ns	V <sub>GS</sub> = - 5 V, I <sub>SD</sub> = 50 A ,T <sub>J</sub> = 25 °C	Note 2
Q <sub>rr</sub>	Reverse Recovery Charge	487		nC	VR = 800 V dif/dt = 2180 A/us	
I <sub>rrm</sub>	Peak Reverse Recovery Current	24		А		
t <sub>rr</sub>	Reverse Recovery Time	67		ns	V <sub>GS</sub> = - 5 V, I <sub>SD</sub> = 50 A ,T <sub>J</sub> = 25 °C	Note 2
Q <sub>rr</sub>	Reverse Recovery Charge	386		nC	VR = 800 V dif/dt = 1320 A/us	
I <sub>rrm</sub>	Peak Reverse Recovery Current	15		А		

Note (2): When using SiC Body Diode the maximum recommended  $V_{\rm GS}$  = -5V

#### **Thermal Characteristics**

S	Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
	$R_{ heta JC}$	Thermal Resistance from Junction to Case	0.24	0.33	°C/W		Fig. 21
	$R_{\theta JC}$	Thermal Resistance from Junction to Ambient		40	l C/VV		





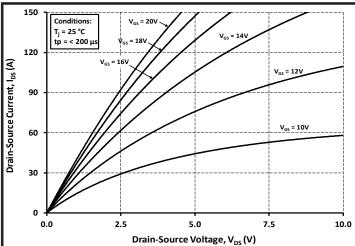
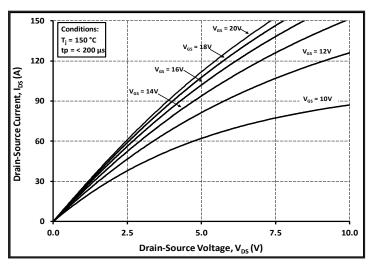


Figure 1. Output Characteristics  $T_J = -55$  °C





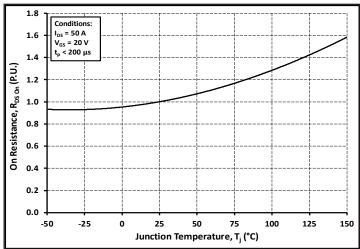
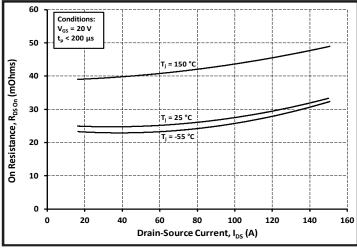
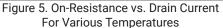


Figure 3. Output Characteristics T<sub>J</sub> = 150 °C

Figure 4. Normalized On-Resistance vs. Temperature





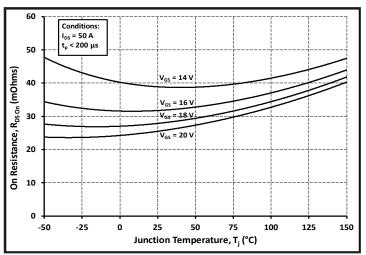
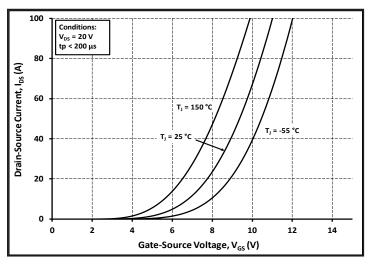


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage





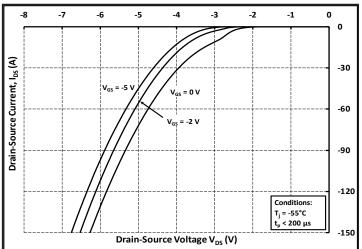


Figure 7. Transfer Characteristic For Various Junction Temperatures

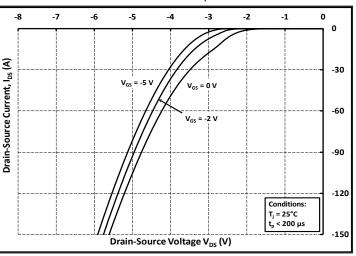


Figure 8. Body Diode Characteristic at -55 °C

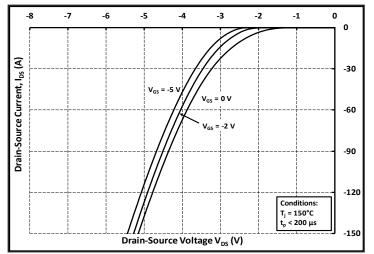


Figure 9. Body Diode Characteristic at 25 °C

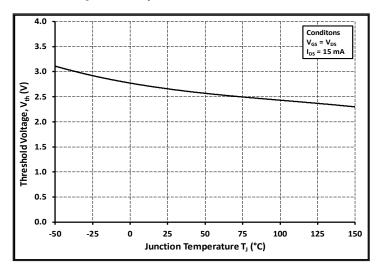


Figure 10. Body Diode Characteristic at 150 °C

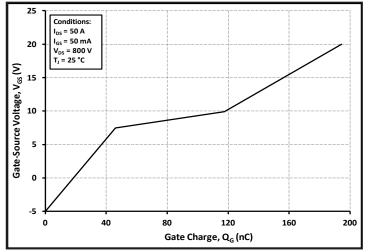
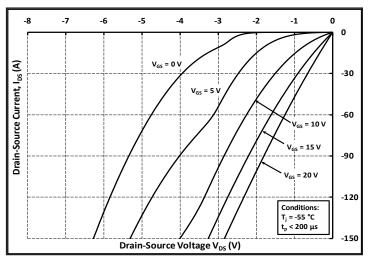


Figure 11. Threshold Voltage vs. Temperature

Figure 12. Gate Charge Characteristic

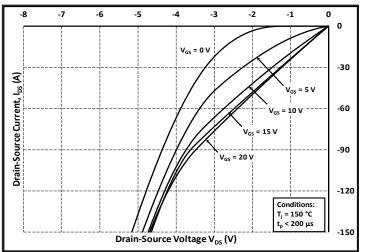




-7 -6 -5 -4 -3 -2 -1 0 -8 Drain-Source Current, I<sub>DS</sub> (A) -30 -60 -90 = 20 V -120 Conditions: t<sub>p</sub> < 200 μs -150 Drain-Source Voltage V<sub>DS</sub> (V)

Figure 13. 3rd Quadrant Characteristic at -55 °C





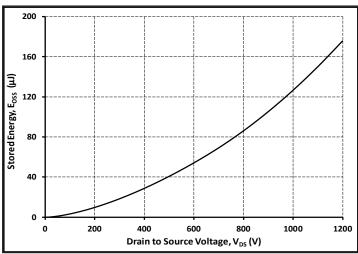
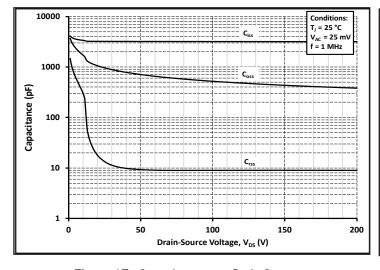


Figure 15. 3rd Quadrant Characteristic at 150 °C

Figure 16. Output Capacitor Stored Energy



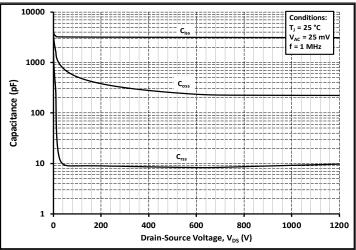


Figure 17. Capacitances vs. Drain-Source Voltage (0-200 V)

Figure 18. Capacitances vs. Drain-Source Voltage (0-1000 V)



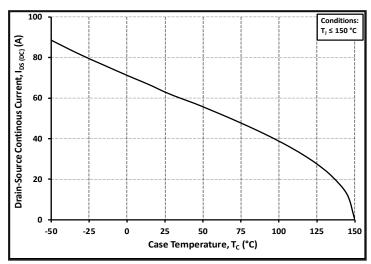
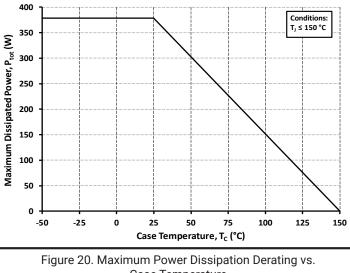


Figure 19. Continuous Drain Current Derating vs. Case Temperature



Case Temperature

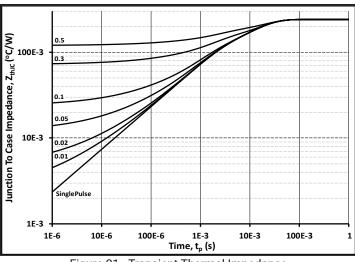


Figure 21. Transient Thermal Impedance (Junction - Case)

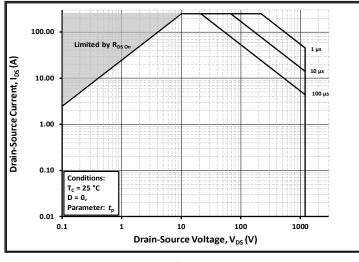


Figure 22. Safe Operating Area

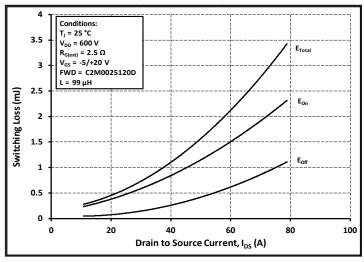


Figure 23. Clamped Inductive Switching Energy vs. Drain Current (V<sub>DD</sub> = 600V)

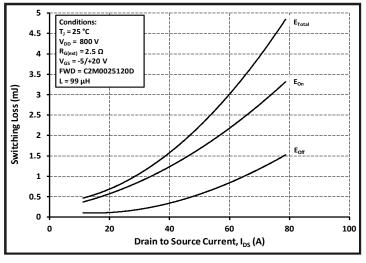


Figure 24. Clamped Inductive Switching Energy vs. Drain Current (V<sub>DD</sub> = 800V)



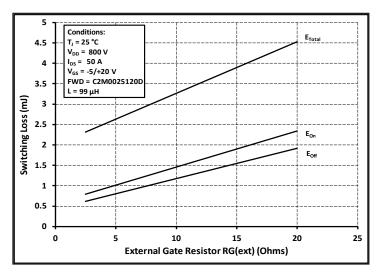


Figure 25. Clamped Inductive Switching Energy vs.  $R_{\text{G(ext)}}$ 

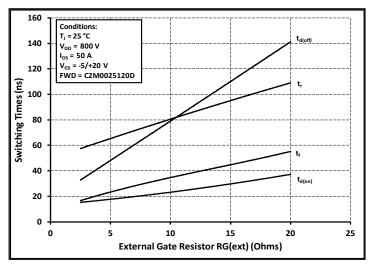


Figure 27. Switching Times vs.  $R_{G(ext)}$ 

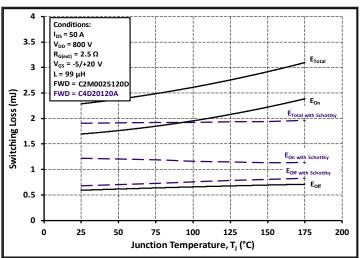


Figure 26. Clamped Inductive Switching Energy vs.
Temperature

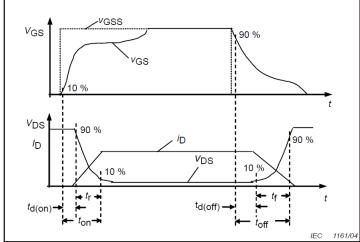


Figure 28. Switching Times Definition



# **Test Circuit Schematic**

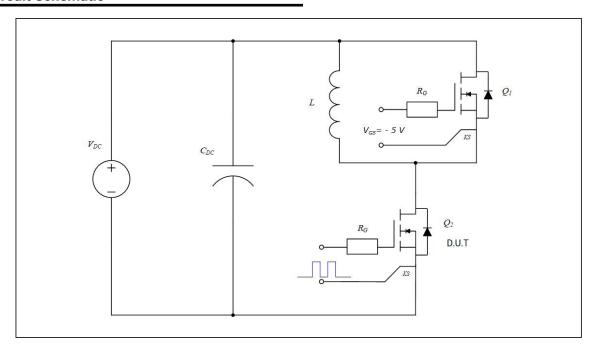


Figure 29. Clamped Inductive Switching Waveform Test Circuit

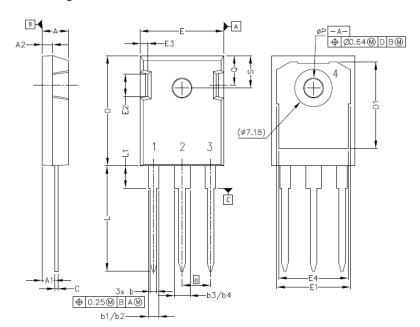
## **ESD Ratings**

ESD Test	Resulting Classification
ESD-HBM	3A (4000V - 8000V)
ESD-CDM	C3 (>=1000V)



# **Package Dimensions**

Package TO-247-3



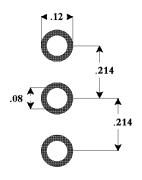


Pinout Information:

- Pin 1 = Gate
- Pin 2, 4 = Drain
- Pin 3 = Source

DOS	Inc	hes	Millimeters		
POS	Min	Max	Min	Max	
А	.190	.205	4.83	5.21	
A1	.090	.100	2.29	2.54	
A2	.075	.085	1.91	2.16	
b	.042	.052	1.07	1.33	
b1	.075	.095	1.91	2.41	
b2	.075	.085	1.91	2.16	
b3	.113	.133	2.87	3.38	
b4	.113	.123	2.87	3.13	
С	.022	.027	0.55	0.68	
D	.819	.831	20.80	21.10	
D1	.640	.695	16.25	17.65	
D2	.037	.049	0.95	1.25	
E	.620	.635	15.75	16.13	
E1	.516	.557	13.10	14.15	
E2	.145	.201	3.68	5.10	
E3	.039	.075	1.00	1.90	
E4	.487	.529	12.38	13.43	
е	.214	BSC	5.44	BSC	
N	3	3	3	3	
L	.780	.800	19.81	20.32	
L1	.161	.173	4.10	4.40	
ØΡ	.138	.144	3.51	3.65	
Q	.216	.236	5.49	6.00	
S	.238	.248	6.04	6.30	
Т	9°	11°	9°	11°	
U	9°	11°	9°	11°	
V	2°	8°	2°	8°	
W	2°	8°	2°	8°	

# **Recommended Solder Pad Layout**



TO-247-3



#### **Notes**

#### RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Cree representative or from the Product Documentation sections of www.cree.com.

#### REACh Compliance

REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a Cree representative to insure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body
nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited
to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical
equipment, aircraft navigation or communication or control systems, air traffic control systems.

#### **Related Links**

- C2M PSPICE Models: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Isolated Gate Driver reference design: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Evaluation Board: http://wolfspeed.com/power/tools-and-support